Chinastandards.org

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ/T 12070-2025

Semiconductor devices - Discrete devices - Reliability test methods for silicon carbide diodes

半导体器件 分立器件 碳化硅二极管可靠性试验方法

(English Translation)

Issued on: December 19, 2025 **Implemented on: July 1, 2026**

Issued by: Ministry of Industry and Information Technology of the People's Republic of China

Preview: page 1 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-t-12070-2025

Chinastandards.org

Table of Contents

Document data

1 Document data

1 Document data

Sector: Electronics (industry standard).

Issuing body: Ministry of Industry and Information Technology of the People's Republic of China.

Date of issue: 2025-12-19.

Date of implementation: 2026-07-01.

Status: valid.

Preview: page 2 of 2 shown, full document available. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-t-12070-2025